

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS80C320	Sep-97	9718 B5	ANAM, K.	DN710449AAB	0.8μ OX/NI	44 PLCC

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-20434

Electrical Cum %
235/0 0.0%

Sonoscan
P-20465

Post Vapor Phase
4/0

Infant / High Voltage Life
125°C, 7.0 V.
P-20466, P-20546

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
231/0	77/1	F1	

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-20547

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
49/0		

Biased Moisture (HAST)
120°C/85% RH, 5.5 V.
P-20548

<u>100 Hr</u>	<u>Cum %</u>

Autoclave
121°C/100% RH, 2 Atmos
P-20549

<u>96 Hr</u>	<u>Cum %</u>
45/0	0.0%

Failure Mode
F1: Leakage

Failure Analysis
In process